

<b>Notic of References Cited</b>	Application/Control No. 10/618,716	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
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	C	US-6,552,415	04-2003	Paul et al.	257/661
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	L	US-			
	M	US-			

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	N	EP 1 383 178 A1	01-2004	EPO	Decroux et al.	H01L 39/16
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.